

650V IGBT Wafer

Ordering Information

| Wafer Name | CD192IG650BF | Chip Name | / |
|------------|--------------|-----------|---|
|------------|--------------|-----------|---|

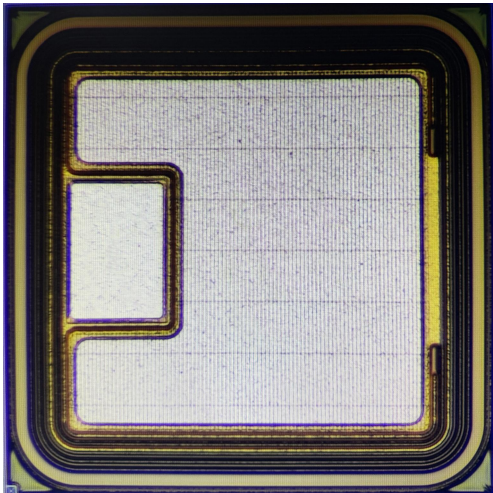
Applications

- Home appliances
- Motor drives
- Fan, Pumps, Vacuum cleaner

Features

- ① Trench field-stop IGBT technology.
- ② High ruggedness performance.
- ③ Positive $V_{CE(sat)}$ temperature coefficient.
- ④ Very tight parameter distribution.

Die outline and Info.

| | |
|--|---|
|  | <p>$V_{CE}=650V, I_c=6A$</p> <p>$V_{CE(sat)}=1.7V$</p> <p>Die Size: $1920\mu m \times 1920\mu m$ (含划片槽)</p> <p>Gate Pad Size: $520\mu m \times 350\mu m$</p> <p>Source Pad Size: As Die Drawing, With PA Layer</p> <p>Back Metal: AlTiNiAg, $1.3\mu m$</p> <p>Front Metal, Thickness: AlSiCu, $5.5\mu m$</p> <p>Gross Die: 7001</p> |
|--|---|

Mechanical Data

| | |
|---|--|
| Nominal Back Metal Composition: | AlTiNiAg $1.3\mu m$ |
| Nominal Front Metal Composition, Thickness: | AlSiCu(98.5%-1%-0.5%) $5.5\mu m$ |
| Wafer Diameter: | 200 mm (8 inch) |
| Wafer Thickness: | $85 \pm 10\mu m$ |
| Minimum Street Width | $80\mu m$ |
| Reject Ink Dot | ink |
| Recommended Storage Environment: | Store in original container, in desiccated nitrogen, with no contamination |
| Recommended Die Attach Conditions: | For optimum electrical results, die attach temperature should not exceed $300^\circ C$ |

Electrical Characteristic Note*

(Device Major Electrical Characteristics for TO-247H package Reference ; $T_{vj}=25^{\circ}\text{C}$ unless otherwise specified.)

| Parameter | Description | Min. | Typ. | Max. | Test Conditions | Unit |
|---------------|---|---|------|-----------|--|--------------------|
| $V_{(BR)CES}$ | Collector-to-Emitter BV | 650 | -- | -- | $V_{GE} = 0\text{V}, I_C = 1\text{mA}$ | V |
| V_{GES} | Gate-to-Emitter Voltage | -- | -- | ± 20 | NA | V |
| I_C | DC collector current | -- | 6 | -- | $T_C = 100^{\circ}\text{C}$ | A |
| I_{CM} | Pulsed collector current | -- | 24 | -- | $V_{GE} = 15\text{V}, t_p$ limited by $T_{vj\text{ max}}$ | A |
| $V_{CE(sat)}$ | Collector-to-Emitter saturation Voltage | -- | 1.7 | 2.0 | $V_{GE} = 15\text{V}, I_C = 6\text{A}$ | V |
| $V_{GE(th)}$ | Gate-to-Emitter Threshold Voltage | 5.7 | 6.2 | 6.7 | $V_{CE} = V_{GE}, I_C = 1\text{mA}$ | V |
| I_{CES} | Collector-to-Emitter Leakage Current | -- | -- | 50 | $V_{CE} = 650\text{V}, V_{GE} = 0\text{V}, T_{vj} = 25^{\circ}\text{C}$ | μA |
| I_{GES} | Gate-to-Emitter Leakage Current | -- | -- | ± 100 | $V_{GE} = \pm 20\text{V}$ | nA |
| C_{ies} | Input capacitance | -- | 480 | -- | $V_{GE} = 0\text{V}, V_{CE} = 25\text{V}, f = 1\text{MHz}$ | pF |
| C_{res} | Reverse transfer capacitance | -- | 8 | -- | | pF |
| $t_{d(on)}$ | Turn-on delay time | -- | 10 | -- | $V_{CC} = 400\text{V}, I_C = 6\text{A}$ $V_{GE} = 0/15\text{V}$ $R_g = 10\Omega$ | ns |
| t_r | Rise time | -- | 8 | -- | | ns |
| $t_{d(off)}$ | Turn-off delay time | -- | 79 | -- | | ns |
| t_f | Fall time | -- | 56 | -- | | ns |
| E_{off} | Turn-off energy | -- | 0.10 | -- | | mJ |
| T_{sc} | Short circuit withstand time | 10 | -- | -- | $V_{GE}=15\text{V}, V_{CE}\leq 400\text{V}, T_J\leq 150^{\circ}\text{C}$ | μs |
| T_{vj} | Operating Junction and | -40 $^{\circ}\text{C}$ to 175 $^{\circ}\text{C}$ Max. | | | | $^{\circ}\text{C}$ |
| T_{STG} | Storage Temperature Range | | | | | |

Note*

Electrical characteristics are reported for the reference packaged part (TO-247H) and can not be guaranteed in die sales form. Variations in customer packaging materials, dimensions and processes may affect parametric performance.

Shipping

- One shipping options is offered as standard.
- Un-sawn wafer

Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.

Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Un-sawn wafers and singulated die can be stored for up to 12 months when in the original sealed packaging at room temperature (45% +/- 15% RH controlled environment).
- Un-sawn wafers and singulated die that have been opened can be stored when returned to their containers and placed in a Nitrogen purged cabinet, at room temperature (45% +/- 15% RH controlled environment).
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

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